

FORM HDP-1449 (Based on Form PTO-1449)

ATTORNEY DOCKET NO.

SERIAL NO.

9319S-000733

10/800,130

## PATENT AND TRADEMARK OFFICE

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

APPLICANT

Yoshihiro KOBAYASHI

FILING DATE

GROUP

3/12/2004

To be assigned

Sheet 1 of 1

## U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.						

## FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.		07-043284	2/14/1995	Japan		X	
2.		10-065525	3/6/1998	Japan		X	

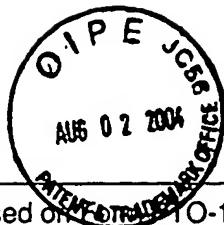
## OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

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Examiner: John Chapman

Date Considered: 9/8/05

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March 12, 2004

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**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation: Yes No	
1.		6-308009		JAPAN		X	
2.		8-29218		JAPAN		X	
3.		2002-39934		JAPAN		X	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
1.		Examination results from corresponding Korean patent application.

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